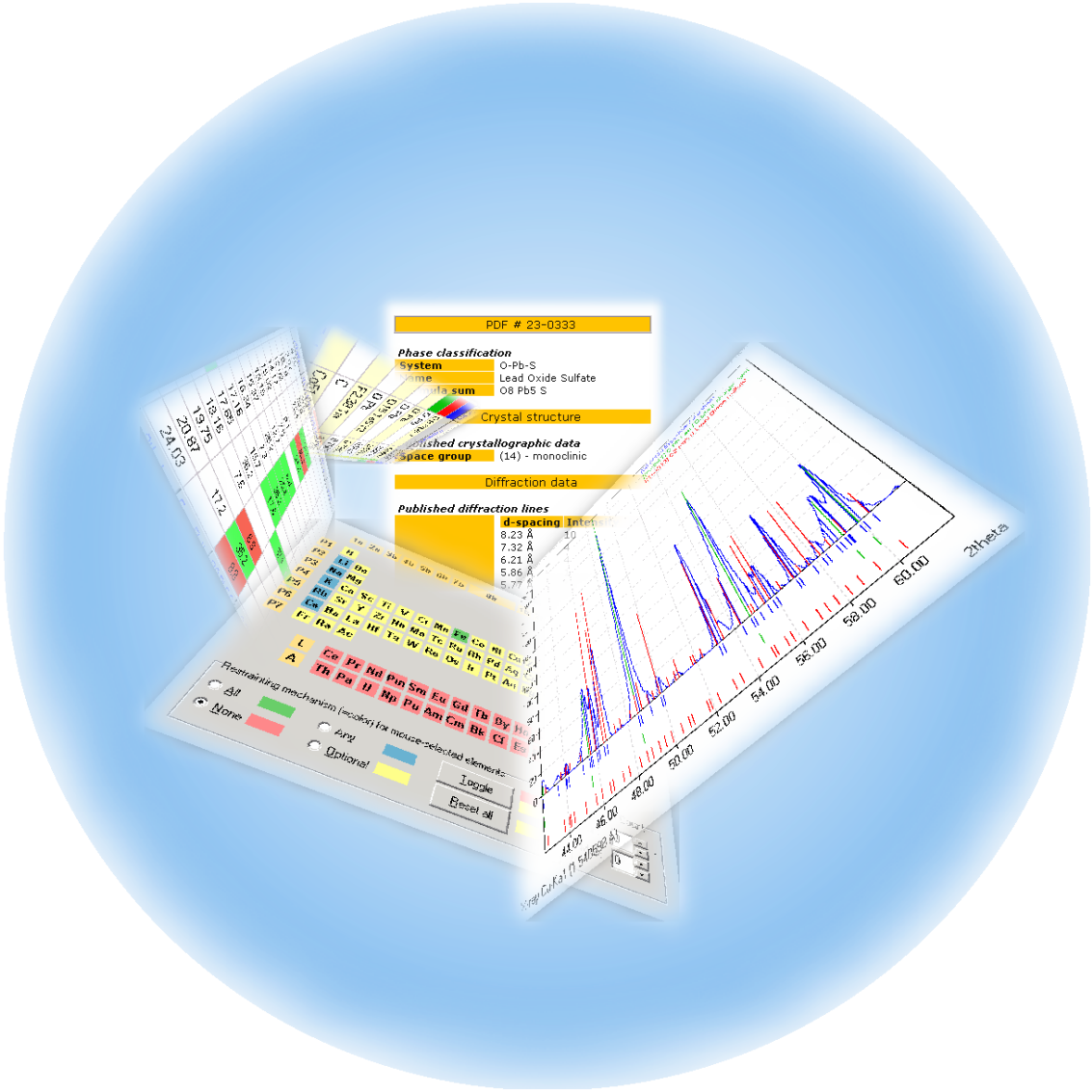
MATCH!

Phase Identification from Powder Diffraction

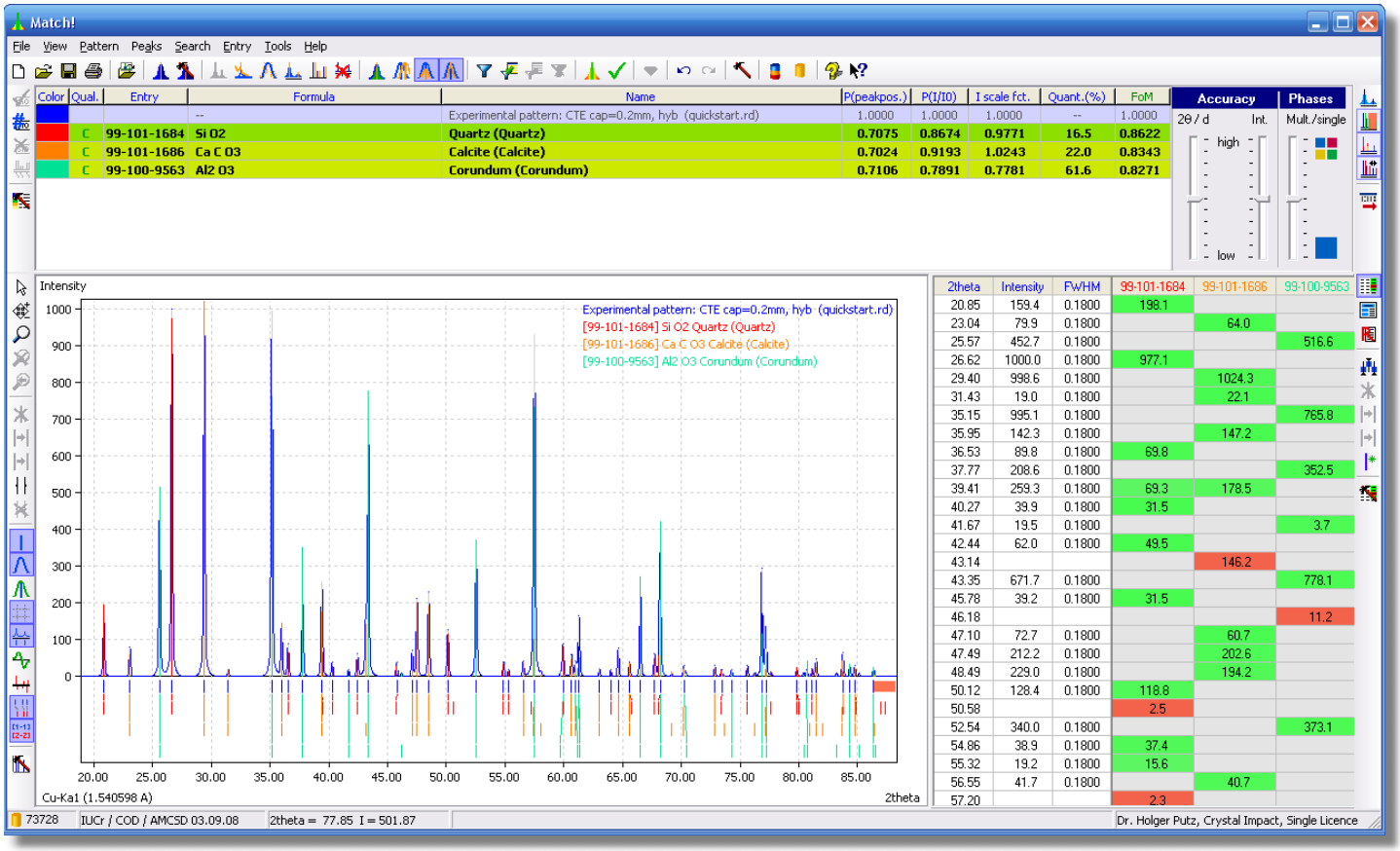


The complete solution for phase identification
... at low costs!

CRYSTAL IMPACT

Match! is an easy-to-use software for phase identification from powder diffraction data. It compares the diffraction pattern of your sample to a database containing reference patterns, in order to identify the phases which are present. Additional knowledge about the sample like elements, color or density can be applied easily. In addition to this **qualitative analysis**, a **semi-quantitative analysis** is performed if I/I_c factors are available for all matching phases.

As reference database, you can apply the included **free-of-charge COD database** and/or any **ICDD PDF** product, use ICSD/Retrieve (if you have a valid licence), and/or create a user database based on your own diffraction patterns. The user database patterns can be edited manually, imported from peak files, calculated from crystal structure data (e.g. CIF files), or imported from your colleague's user database.



Features

- Fast single and multiple phase identification from powder diffraction data
- Use **free-of-charge reference patterns** calculated from the **COD** (incl. I/I_c), **any ICDD PDF database**, any **ICSD/ Retrieve version** (release 1993-2002; valid licence required) and/or your own diffraction data in phase identification
- Comfortable user database manager for easy maintenance of user data (add/import/edit/delete/sort entries)
- Fully integrated handling of your own diffraction data with PDF or other reference data (search-match, retrieval, data viewing)
- Automatic residual searching with respect to identified phases
- Automatic raw data processing including peak searching, profile fitting and 2theta error correction
- Comfortable editing of peaks (add/shift/delete/fit to exp. profile)
- Semi-quantitative analysis (Reference Intensity Ratio method)
- Straight-forward usage of additional knowledge (composition, crystallographic data, color, density etc.)
- Multiple step undo/redo
- Large variety of supported diffraction data file formats: http://www.crystalimpact.com/match/functions.htm

System requirements

- Microsoft Windows 98, ME, NT4, 2000, XP, Vista or Windows 7
- Microsoft Internet Explorer 5.01 (or higher)
- 128 MB of RAM (256 MB recommended)
- 600 MB of free disc space
- DVD drive
- **Supported diffraction data file formats (automatic recognition)**: Bruker/Siemens, DBWS, Inel, Ital Structures, Jade/MDI/SCINTAG, JEOL Export, PANalytical/Philips, Rigaku, SCINTAG, Shimadzu, various text files (profile or peak list data), Siemens, Sietronics, Stoe

Prices*

	non-profit org.	profit org.
Single licence	499 €	998 €
Site licence**	998 €	1,996 €
Campus licence***	1,996 €	3,992 €

* Prices do not include taxes which may be due.
** Unlimited number of installations within one institute/dept.
*** Unlimited number of installations within one university/company.

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